CLAIMS

What is claimed is:

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An application specific integrated circuit (ASIC) comprising:

 a standard cell, the standard cell including a plurality of logic functions;
 at least one bus coupled to at least a portion of the logic functions;
 a plurality of internal signals from the plurality of logic functions; and
 a field programmable (FP) function coupled to the at least one bus and at least a portion
 of the plurality of internal signals, wherein the FP function provides access to internal signals

 for observation and control.

- 2. The ASIC of claim 1 wherein the FP function comprises a signal connector function.
- 3. The ASIC of claim 2 wherein the signal connector function comprises a first logic for providing an external I/O function and a second logic which is in communication with the first logic that selects the appropriate internal signals for external observation and control.
 - 4. The ASIC of claim 1 wherein the FP function includes a testing function.
- 5. The ASIC of claim 4 wherein the testing function includes a selector function for selecting the signals of interest and a validation function coupled to the selector function for testing the signals of interest.

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- 6. The ASIC of claim 5 wherein the testing function includes a test program for validating at least one of the plurality of logic functions.
- The ASIC of claim 1 wherein the FP function includes an error recovery function.
 - 8. The ASIC of claim 7 wherein the error recovery function comprises determining if an error is observed, determining the error case when an error is observed and corrected.
 - 9. The ASIC of claim 8 wherein the error recovery function further includes writing an error code to an external system based upon the error case.
 - 10. The ASIC of claim 8 wherein the error recovery function utilizes a watchdog function.
 - 11. The ASIC of claim 9 wherein the watchdog function comprises determining after a predetermined time-period or number of actions if a portion of the ASIC is operating properly, and invoking an error-handling process if the portion is not operating properly.
 - 12. The ASIC of claim 1 wherein the FP function comprises a field programmable gate array function.

- 13. A method for providing a testing function in an application specific integrated circuit (ASIC), the ASIC including a standard cell, the standard cell including a plurality of logic functions, the method comprising the steps of:
 (a) providing a field programmable (FP) function in the ASIC; and
 (b) providing a test program in the FP function.
- 14. The method of claim 13 wherein the test program validates at least one of the plurality of logic functions.
- 15. A method for allowing an application specific integrated circuit to operate after an error has occurred therein, the method comprising the steps of:
 - (a) providing a field programmable (FP) function in the ASIC; and
 - (b) providing an error recovery function within the FP function.
- 16. The ASIC of claim 15 wherein the error recovery function comprises determining if an error is observed, determining the error case when an error is observed and corrected.
- 17. The ASIC of claim 16 wherein the error recovery function further includes writing an error code to an external system based upon the error case.
- 18. The ASIC of claim 16 wherein the error recovery function utilizes a watchdog function.

19. The ASIC of claim 18 wherein the watchdog function comprises determining after a predetermined time-period or number of actions if a portion of the ASIC is operating properly, and invoking an error-handling process if the portion is not operating properly.